

# EEPROM Serial 4-Kb Microwire - Automotive Grade 1

## CAV93C66

### Description

The CAV93C66 is an EEPROM Serial 4-Kb Microwire Automotive Grade 1 device which is organized as either 256 registers of 16 bits (ORG pin at V<sub>CC</sub>) or 512 registers of 8 bits (ORG pin at GND). Each register can be written (or read) serially by using the DI (or DO) pin. The device features sequential read and self-timed internal write with auto-clear. On-chip Power-On Reset circuitry protects the internal logic against powering up in the wrong state.

### Features

- Automotive AEC-Q100 Grade 1 (–40°C to +125°C) Qualified
- High Speed Operation: 2 MHz
- 2.5 V to 5.5 V Supply Voltage Range
- Selectable x8 or x16 Memory Organization
- Self-timed Write Cycle with Auto-clear
- Sequential Read
- Software Write Protection
- Power-up Inadvertent Write Protection
- Low Power CMOS Technology
- 1,000,000 Program/Erase Cycles
- 100 Year Data Retention
- 8-lead SOIC and TSSOP Packages
- These Devices are Pb-Free, Halogen Free/BFR Free, and RoHS Compliant

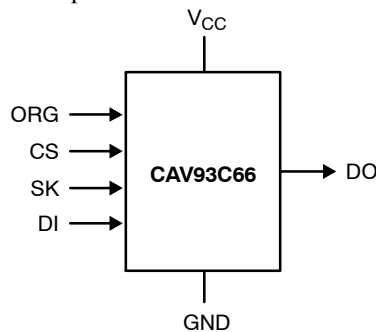
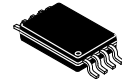


Figure 1. Functional Symbol

Note: When the ORG pin is connected to V<sub>CC</sub>, the x16 organization is selected. When it is connected to ground, the x8 organization is selected. If the ORG pin is left unconnected, then an internal pull-up device will select the x16 organization.



SOIC-8  
V SUFFIX  
CASE 751BD



TSSOP-8  
Y SUFFIX  
CASE 948AL

### PIN CONFIGURATIONS



SOIC (V), TSSOP (Y)  
(Top View)

### PIN FUNCTION

| Pin Name        | Function            |
|-----------------|---------------------|
| CS              | Chip Select         |
| SK              | Clock Input         |
| DI              | Serial Data Input   |
| DO              | Serial Data Output  |
| V <sub>CC</sub> | Power Supply        |
| GND             | Ground              |
| ORG             | Memory Organization |
| NC              | No Connection       |

### ORDERING INFORMATION

See detailed ordering and shipping information on page 8 of this data sheet.

**Table 1. ABSOLUTE MAXIMUM RATINGS**

| Parameters                                         | Ratings      | Units |
|----------------------------------------------------|--------------|-------|
| Storage Temperature                                | -65 to +150  | °C    |
| Voltage on Any Pin with Respect to Ground (Note 1) | -0.5 to +6.5 | V     |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. The DC input voltage on any pin should not be lower than -0.5 V or higher than  $V_{CC} + 0.5$  V. During transitions, the voltage on any pin may undershoot to no less than -1.5 V or overshoot to no more than  $V_{CC} + 1.5$  V, for periods of less than 20 ns.

**Table 2. RELIABILITY CHARACTERISTICS** (Note 2)

| Symbol             | Parameter      | Min       | Units                  |
|--------------------|----------------|-----------|------------------------|
| $N_{END}$ (Note 3) | Endurance      | 1,000,000 | Program / Erase Cycles |
| $T_{DR}$           | Data Retention | 100       | Years                  |

2. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.
3. Block Mode,  $V_{CC} = 5$  V, 25°C.

**Table 3. D.C. OPERATING CHARACTERISTICS** ( $V_{CC} = +2.5$  V to +5.5 V,  $T_A = -40^\circ\text{C}$  to +125°C unless otherwise specified.)

| Symbol    | Parameter                  | Test Conditions                                                                      | Min                 | Max                 | Units         |
|-----------|----------------------------|--------------------------------------------------------------------------------------|---------------------|---------------------|---------------|
| $I_{CC1}$ | Supply Current (Write)     | $V_{CC} = 5.0$ V                                                                     |                     | 1                   | mA            |
| $I_{CC2}$ | Supply Current (Read)      | DO open, $f_{SK} = 2$ MHz, $V_{CC} = 5.0$ V                                          |                     | 500                 | $\mu\text{A}$ |
| $I_{SB1}$ | Standby Current (x8 Mode)  | $V_{IN} = \text{GND or } V_{CC}$<br>$CS = \text{GND, ORG} = \text{GND}$              |                     | 5                   | $\mu\text{A}$ |
| $I_{SB2}$ | Standby Current (x16 Mode) | $V_{IN} = \text{GND or } V_{CC}$<br>$CS = \text{GND, ORG} = \text{Float or } V_{CC}$ |                     | 3                   | $\mu\text{A}$ |
| $I_{LI}$  | Input Leakage Current      | $V_{IN} = \text{GND to } V_{CC}$                                                     |                     | 2                   | $\mu\text{A}$ |
| $I_{LO}$  | Output Leakage Current     | $V_{OUT} = \text{GND to } V_{CC}$ $CS = \text{GND}$                                  |                     | 2                   | $\mu\text{A}$ |
| $V_{IL1}$ | Input Low Voltage          | $4.5 \text{ V} \leq V_{CC} < 5.5 \text{ V}$                                          | -0.1                | 0.8                 | V             |
| $V_{IH1}$ | Input High Voltage         | $4.5 \text{ V} \leq V_{CC} < 5.5 \text{ V}$                                          | 2                   | $V_{CC} + 1$        | V             |
| $V_{IL2}$ | Input Low Voltage          | $2.5 \text{ V} \leq V_{CC} < 4.5 \text{ V}$                                          | 0                   | $V_{CC} \times 0.2$ | V             |
| $V_{IH2}$ | Input High Voltage         | $2.5 \text{ V} \leq V_{CC} < 4.5 \text{ V}$                                          | $V_{CC} \times 0.7$ | $V_{CC} + 1$        | V             |
| $V_{OL1}$ | Output Low Voltage         | $4.5 \text{ V} \leq V_{CC} < 5.5 \text{ V}$ , $I_{OL} = 3$ mA                        |                     | 0.4                 | V             |
| $V_{OH1}$ | Output High Voltage        | $4.5 \text{ V} \leq V_{CC} < 5.5 \text{ V}$ , $I_{OH} = -400 \mu\text{A}$            | 2.4                 |                     | V             |
| $V_{OL2}$ | Output Low Voltage         | $2.5 \text{ V} \leq V_{CC} < 4.5 \text{ V}$ , $I_{OL} = 1$ mA                        |                     | 0.2                 | V             |
| $V_{OH2}$ | Output High Voltage        | $2.5 \text{ V} \leq V_{CC} < 4.5 \text{ V}$ , $I_{OH} = -100 \mu\text{A}$            | $V_{CC} - 0.2$      |                     | V             |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

**Table 4. PIN CAPACITANCE** ( $T_A = 25^\circ\text{C}$ ,  $f = 1.0$  MHz,  $V_{CC} = +5.0$  V)

| Symbol             | Test                                | Conditions      | Min | Typ | Max | Units |
|--------------------|-------------------------------------|-----------------|-----|-----|-----|-------|
| $C_{OUT}$ (Note 4) | Output Capacitance (DO)             | $V_{OUT} = 0$ V |     |     | 5   | pF    |
| $C_{IN}$ (Note 4)  | Input Capacitance (CS, SK, DI, ORG) | $V_{IN} = 0$ V  |     |     | 5   | pF    |

4. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.

**Table 5. POWER-UP TIMING** (Notes 5, 6)

| Symbol    | Parameter                   | Max | Units |
|-----------|-----------------------------|-----|-------|
| $t_{PUR}$ | Power-up to Read Operation  | 1   | ms    |
| $t_{PUW}$ | Power-up to Write Operation | 1   | ms    |

5. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.

6.  $t_{PUR}$  and  $t_{PUW}$  are the delays required from the time  $V_{CC}$  is stable until the specified operation can be initiated.

**Table 6. A.C. TEST CONDITIONS**

|                           |                                                                     |                                 |
|---------------------------|---------------------------------------------------------------------|---------------------------------|
| Input Rise and Fall Times | ≤ 50 ns                                                             |                                 |
| Input Pulse Voltages      | 0.4 V to 2.4 V                                                      | 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V |
| Timing Reference Voltages | 0.8 V, 2.0 V                                                        | 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V |
| Input Pulse Voltages      | 0.2 V <sub>CC</sub> to 0.7 V <sub>CC</sub>                          | 2.5 V ≤ V <sub>CC</sub> ≤ 4.5 V |
| Timing Reference Voltages | 0.5 V <sub>CC</sub>                                                 | 2.5 V ≤ V <sub>CC</sub> ≤ 4.5 V |
| Output Load               | Current Source I <sub>OLmax</sub> /I <sub>OHmax</sub> ; CL = 100 pF |                                 |

**Table 7. A.C. CHARACTERISTICS** ( $V_{CC} = +2.5\text{ V}$  to  $+5.5\text{ V}$ ,  $T_A = -40^\circ\text{C}$  to  $+125^\circ\text{C}$ , unless otherwise specified.)

| Symbol            | Parameter                    | Min  | Max  | Units         |
|-------------------|------------------------------|------|------|---------------|
| $t_{CSS}$         | CS Setup Time                | 50   |      | ns            |
| $t_{CSH}$         | CS Hold Time                 | 0    |      | ns            |
| $t_{DIS}$         | DI Setup Time                | 100  |      | ns            |
| $t_{DIH}$         | DI Hold Time                 | 100  |      | ns            |
| $t_{PD1}$         | Output Delay to 1            |      | 0.25 | $\mu\text{s}$ |
| $t_{PD0}$         | Output Delay to 0            |      | 0.25 | $\mu\text{s}$ |
| $t_{HZ}$ (Note 7) | Output Delay to High-Z       |      | 100  | ns            |
| $t_{EW}$          | Program/Erase Pulse Width    |      | 5    | ms            |
| $t_{CSMIN}$       | Minimum CS Low Time          | 0.25 |      | $\mu\text{s}$ |
| $t_{SKHI}$        | Minimum SK High Time         | 0.25 |      | $\mu\text{s}$ |
| $t_{SKLOW}$       | Minimum SK Low Time          | 0.25 |      | $\mu\text{s}$ |
| $t_{SV}$          | Output Delay to Status Valid |      | 0.25 | $\mu\text{s}$ |
| $SK_{MAX}$        | Maximum Clock Frequency      | DC   | 2000 | kHz           |

7. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.

## DEVICE OPERATION

The CAV93C66 is a 4096-bit nonvolatile memory intended for use with industry standard microprocessors. The CAV93C66 can be organized as either registers of 16 bits or 8 bits. When organized as X16, seven 11-bit instructions control the reading, writing and erase operations of the device. When organized as X8, seven 12-bit instructions control the reading, writing and erase operations of the device. The device operates on a single power supply and will generate on chip, the high voltage required during any write operation.

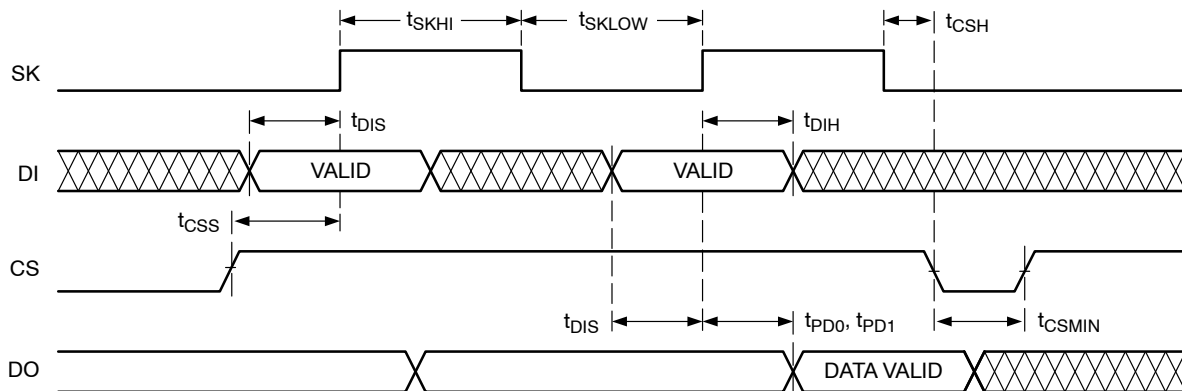
Instructions, addresses, and write data are clocked into the DI pin on the rising edge of the clock (SK). The DO pin is normally in a high impedance state except when reading data from the device, or when checking the ready/busy status after a write operation. The serial communication protocol follows the timing shown in Figure 2.

The ready/busy status can be determined after the start of internal write cycle by selecting the device (CS high) and polling the DO pin; DO low indicates that the write operation is not completed, while DO high indicates that the device is ready for the next instruction. If necessary, the DO pin may be placed back into a high impedance state during chip select by shifting a dummy “1” into the DI pin. The DO pin will enter the high impedance state on the rising edge of the clock (SK). Placing the DO pin into the high impedance state is recommended in applications where the DI pin and the DO pin are to be tied together to form a common DI/O pin.

The format for all instructions sent to the device is a logical “1” start bit, a 2-bit (or 4-bit) opcode, 8-bit address (an additional bit when organized X8) and for write operations a 16-bit data field (8-bit for X8 organizations). The instruction format is shown in Instruction Set table.

**Table 8. INSTRUCTION SET**

| Instruction | Start Bit | Opcode | Address   |           | Data  |        | Comments              |
|-------------|-----------|--------|-----------|-----------|-------|--------|-----------------------|
|             |           |        | x8        | x16       | x8    | x16    |                       |
| READ        | 1         | 10     | A8-A0     | A7-A0     |       |        | Read Address AN – A0  |
| ERASE       | 1         | 11     | A8-A0     | A7-A0     |       |        | Clear Address AN – A0 |
| WRITE       | 1         | 01     | A8-A0     | A7-A0     | D7-D0 | D15-D0 | Write Address AN – A0 |
| EWEN        | 1         | 00     | 11XXXXXXX | 11XXXXXXX |       |        | Write Enable          |
| EWDS        | 1         | 00     | 00XXXXXXX | 00XXXXXXX |       |        | Write Disable         |
| ERAL        | 1         | 00     | 10XXXXXXX | 10XXXXXXX |       |        | Clear All Addresses   |
| WRAL        | 1         | 00     | 01XXXXXXX | 01XXXXXXX | D7-D0 | D15-D0 | Write All Addresses   |



**Figure 2. Synchronous Data Timing**

## Read

Upon receiving a READ command and an address (clocked into the DI pin), the DO pin of the CAV93C66 will come out of the high impedance state and, after sending an initial dummy zero bit, will begin shifting out the data addressed (MSB first). The output data bits will toggle on the rising edge of the SK clock and are stable after the specified time delay ( $t_{PD0}$  or  $t_{PD1}$ ).

For the CAV93C66 after the initial data word has been shifted out and CS remains asserted with the SK clock continuing to toggle, the device will automatically increment to the next address and shift out the next data word in a sequential READ mode. As long as CS is continuously asserted and SK continues to toggle, the device will keep incrementing to the next address automatically until it reaches to the end of the address space, then loops back to address 0. In the sequential READ mode, only the initial data

word is preceded by a dummy zero bit. All subsequent data words will follow without a dummy zero bit. The READ instruction timing is illustrated in Figure 3.

## Erase/Write Enable and Disable

The device powers up in the write disable state. Any writing after power-up or after an EWDS (erase/write disable) instruction must first be preceded by the EWEN (erase/write enable) instruction. Once the write instruction is enabled, it will remain enabled until power to the device is removed, or the EWDS instruction is sent. The EWDS instruction can be used to disable all CAV93C66 write and erase instructions, and will prevent any accidental writing or clearing of the device. Data can be read normally from the device regardless of the write enable/disable status. The EWEN and EWDS instructions timing is shown in Figure 4.

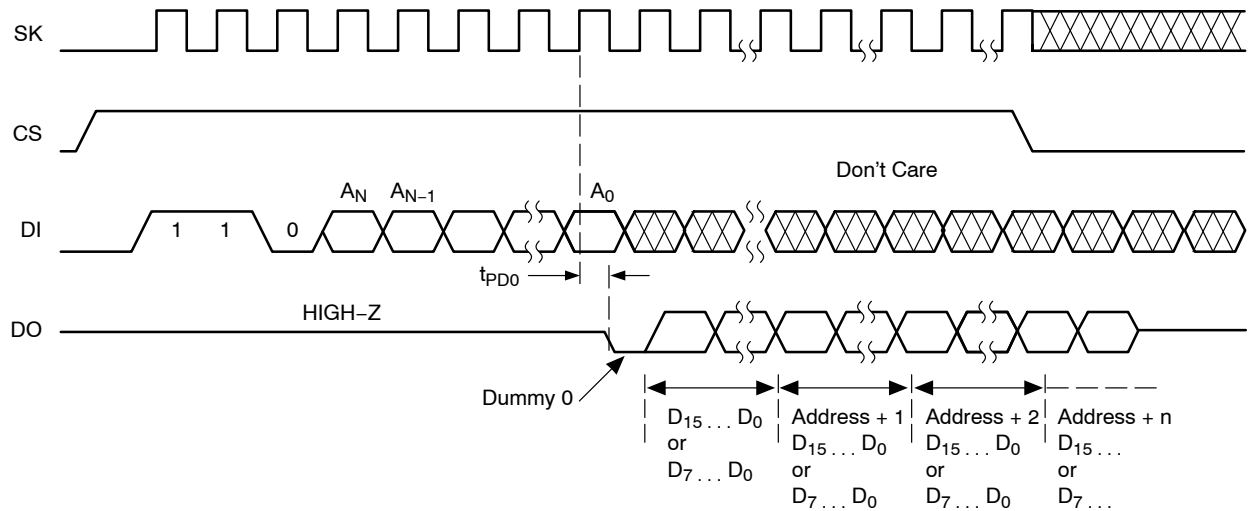


Figure 3. READ Instruction Timing

### Write

After receiving a WRITE command (Figure 5), address and the data, the CS (Chip Select) pin must be deselected for a minimum of  $t_{CSMIN}$ . The falling edge of CS will start the self clocking clear and data store cycle of the memory location specified in the instruction. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the CAV93C66 can be determined by selecting the device and polling the DO pin. Since this device features Auto-Clear before write, it is NOT necessary to erase a memory location before it is written into.

### Erase

Upon receiving an ERASE command and address, the CS (Chip Select) pin must be deasserted for a minimum of  $t_{CSMIN}$  (Figure 6). The falling edge of CS will start the self clocking clear cycle of the selected memory location. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the CAV93C66 can be determined by selecting the device and polling the DO pin. Once cleared, the content of a cleared location returns to a logical "1" state.

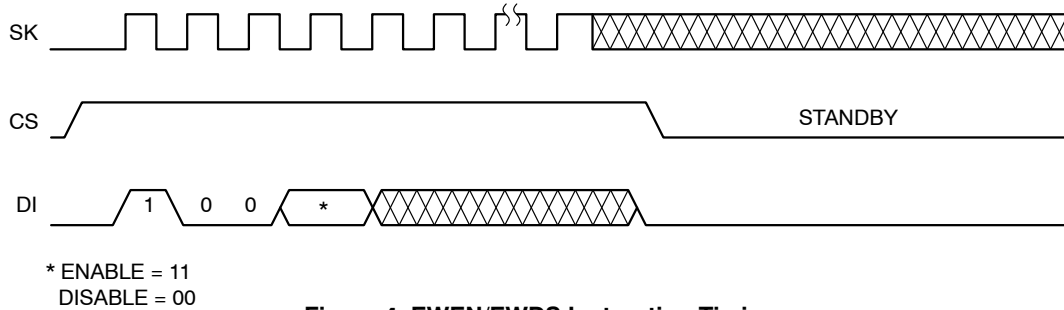


Figure 4. EWEN/EWDS Instruction Timing

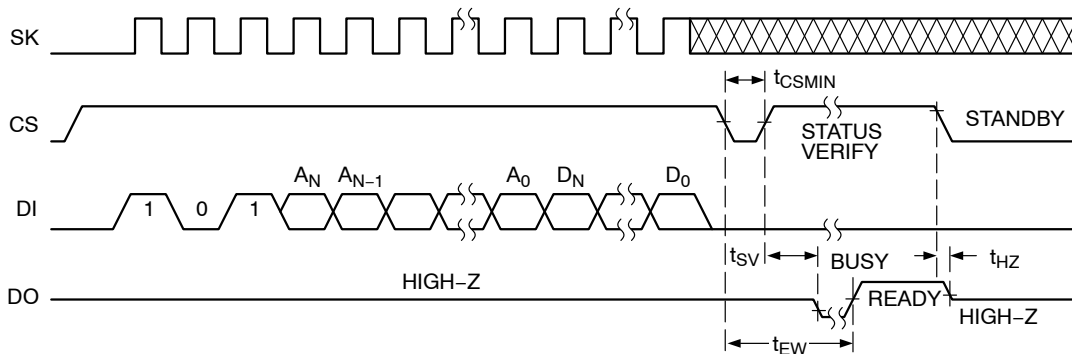


Figure 5. Write Instruction Timing

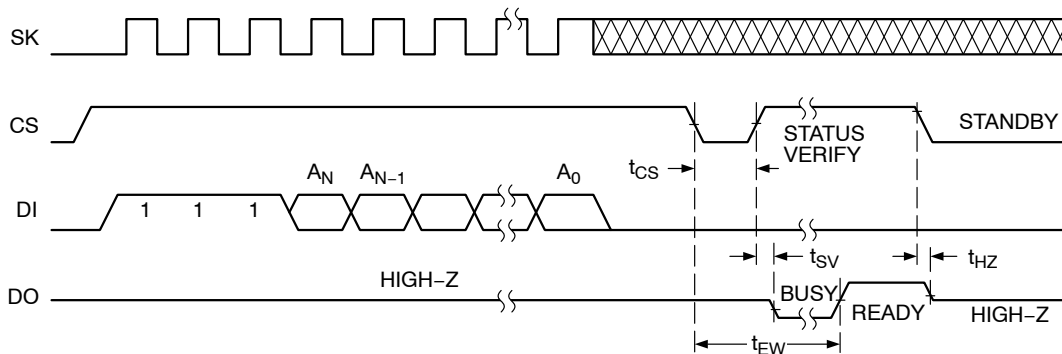


Figure 6. Erase Instruction Timing

### Erase All

Upon receiving an ERAL command (Figure 7), the CS (Chip Select) pin must be deselected for a minimum of  $t_{CSMIN}$ . The falling edge of CS will start the self clocking clear cycle of all memory locations in the device. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the device can be determined by selecting the device and polling the DO pin. Once cleared, the contents of all memory bits return to a logical “1” state.

### Write All

Upon receiving a WRAL command and data, the CS (Chip Select) pin must be deselected for a minimum of  $t_{CSMIN}$  (Figure 8). The falling edge of CS will start the self clocking data write to all memory locations in the device. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the device can be determined by selecting the device and polling the DO pin. It is not necessary for all memory locations to be cleared before the WRAL command is executed.

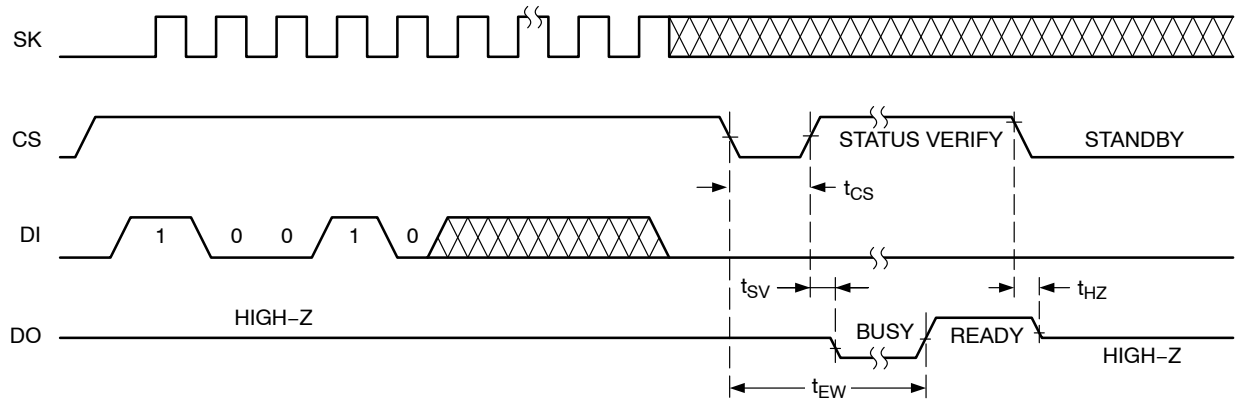


Figure 7. ERAL Instruction Timing

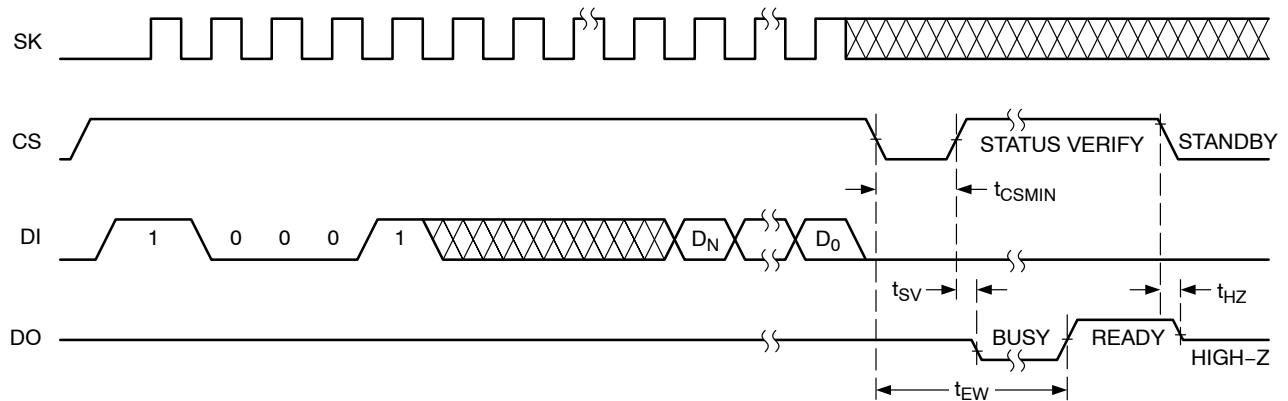


Figure 8. WRAL Instruction Timing

## CAV93C66

### ORDERING INFORMATION

| Device Order Number | Specific Device Marking | Package Type  | Temperature Range | Lead Finish | Shipping <sup>†</sup>              |
|---------------------|-------------------------|---------------|-------------------|-------------|------------------------------------|
| CAV93C66VE-GT3      | 93C66D                  | SOIC-8, JEDEC | -40°C to +125°C   | NiPdAu      | Tape & Reel,<br>3,000 Units / Reel |
| CAV93C66YE-GT3      | M66D                    | TSSOP-8       | -40°C to +125°C   | NiPdAu      | Tape & Reel,<br>3,000 Units / Reel |

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

8. All packages are RoHS-compliant (Lead-free, Halogen-free).

9. The standard lead finish is NiPdAu.

10. For detailed information and a breakdown of device nomenclature and numbering systems, please see the **onsemi** Device Nomenclature document, TND310/D, available at [www.onsemi.com](http://www.onsemi.com)

**SOIC-8, 150 mils**  
**CASE 751BD**  
**ISSUE O**

DATE 19 DEC 2008



**TOP VIEW**

| SYMBOL   | MIN      | NOM | MAX  |
|----------|----------|-----|------|
| A        | 1.35     |     | 1.75 |
| A1       | 0.10     |     | 0.25 |
| b        | 0.33     |     | 0.51 |
| c        | 0.19     |     | 0.25 |
| D        | 4.80     |     | 5.00 |
| E        | 5.80     |     | 6.20 |
| E1       | 3.80     |     | 4.00 |
| e        | 1.27 BSC |     |      |
| h        | 0.25     |     | 0.50 |
| L        | 0.40     |     | 1.27 |
| $\theta$ | 0°       |     | 8°   |



**SIDE VIEW**



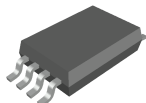
**END VIEW**

**Notes:**

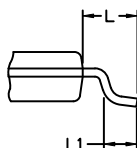
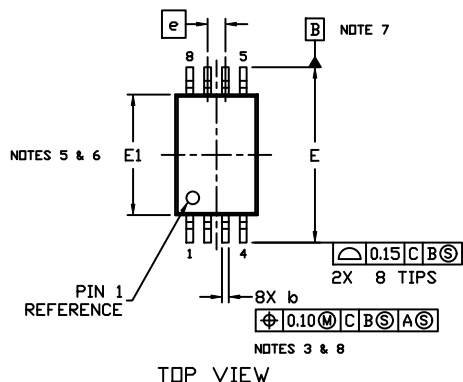
- (1) All dimensions are in millimeters. Angles in degrees.
- (2) Complies with JEDEC MS-012.

|                         |                         |                                                                                                                                                                                     |
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| <b>DESCRIPTION:</b>     | <b>SOIC-8, 150 MILS</b> | <b>PAGE 1 OF 1</b>                                                                                                                                                                  |

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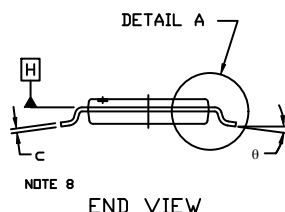
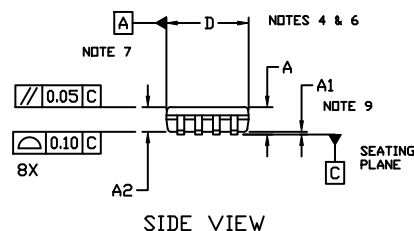

**TSSOP8, 4.4x3.0, 0.65P**  
**CASE 948AL**  
**ISSUE A**

DATE 20 MAY 2022

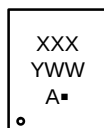


## NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5, 2009.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL NOT BE 0.15 IN EXCESS OF MAXIMUM MATERIAL CONDITION.
4. DIMENSION D DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 PER SIDE.
5. DIMENSION E1 DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 PER SIDE.
6. THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM. DIMENSIONS D AND E1 ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM PLANE H.
7. DATUMS A AND B ARE TO BE DETERMINED AT DATUM H.
8. DIMENSIONS b AND c APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10 AND 0.25 FROM THE LEAD TIP.
9. A1 IS DEFINED AS THE LOWEST VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

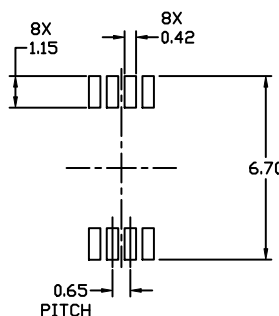


| DIM | MILLIMETERS |      |      |
|-----|-------------|------|------|
|     | MIN.        | NDM. | MAX. |
| A   | ---         | ---  | 1.20 |
| A1  | 0.05        | ---  | 0.15 |
| A2  | 0.80        | 0.90 | 1.05 |
| b   | 0.19        | ---  | 0.30 |
| c   | 0.09        | ---  | 0.20 |
| D   | 2.90        | 3.00 | 3.10 |
| E   | 6.30        | 6.40 | 6.50 |
| E1  | 4.30        | 4.40 | 4.50 |
| e   | 0.65 BSC    |      |      |
| L   | 1.00 REF    |      |      |
| L1  | 0.50        | 0.60 | 0.70 |
| θ   | 0°          | ---  | 8°   |

**GENERIC**  
**MARKING DIAGRAM\***


XXX = Specific Device Code  
Y = Year  
WW = Work Week  
A = Assembly Location  
▪ = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.


**RECOMMENDED**  
**MOUNTING FOOTPRINT\***

\* For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

|                         |                               |                                                                                                                                                                                  |
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| <b>DESCRIPTION:</b>     | <b>TSSOP8, 4.4X3.0, 0.65P</b> | <b>PAGE 1 OF 1</b>                                                                                                                                                               |

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